

<b>Appl</b> i	ication	/Control	No.
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Applicant(s)/Patent under Reexamination

KATANO, SEIICHI

10/639,052

Examiner

Art Unit

Tadesse Hailu

2173

SEARCHED					
Class	Subclass	Date	Examiner		
715	744-748	5/3/2007	т <b>н</b>		
715	740, 866	5/3/2007	TH		
715	738, 736	5/3/2007	TH		
715	762-765	5/3/2007	тн		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
715	744-748	5/3/2007	ТН	
715	736, 738	5/3/2007	тн	
715	762-765	5/3/2007	TH	
PGPUB - CLM searched - search history enclosed		5/3/2007	th	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST - Searched all databases (USPAT, PGPUB, IBM-TDB, DERWENT, EPO,&JPO)	5/3/2007	тн		
google.com - searched forcustomization OR customizing "mutifucntion peripherals" OR multi function peripherals OR MFP	5/3/2007	ТН		
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